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Technical Papers

Day 1: Monday – October 12, 2015

Session 1	Memories and Emerging Technologies
Date / Time	Monday, October 12, 2015/11:25 AM – 12:25 PM
Session Chair	Salvatore Pontarelli, CNIT, Italy

- ▶ **Evaluating the Impact of Spike and Flicker Noise in Phase Change Memories** 1
Salin Junsangri, Fabrizio Lombardi and Jie Han
- ▶ **Fault Detection and Repair of DSC Arrays Through Memristor Sensing** 7
J. Mathew, Y. Yang, M. Ottavi, T. Brown, A. Zampetti, A. Di Carlo, A. M. Jabir and D. K. Pradhan
- ▶ **Asymmetric ECC Organization in 3D-Memory via Spare Column Utilization** 13
Hyunseung Han and Joon-Sung Yang
- ▶ **Exploring Error-Tolerant Low-Power Multiple-output Read Scheme for Memristor-Based Memory Arrays** 17
Adedotun A. Adeyemo, Jimson Mathew, Abusaleh M. Jabir and Dhiraj K. Pradhan

Session 2	Best Paper Candidates
Date / Time	Monday, October 12, 2015/01:50 PM– 03:30 PM
Session Chair	Fabrizio Lombardi, Northeastern University

- ▶ **RotR: Rotational Redundant Task Mapping for Fail-operational MPSoCs** 21
Badrun Nahar and Brett H. Meyer
- ▶ **On Enhancing the Debug Architecture of a System-on-Chip (SoC) to Detect Software Attacks** 29
Jerry Backer, David Hély and Ramesh Karri
- ▶ **Software-Based On-Chip Thermal Sensor Calibration for DVFS-enabled Many-core Systems** 35
Sami Teräväinen, Mohammad-Hashem Haghbayan, Amir-Mohammad Rahmani, Pasi Liljeberg and Hannu Tenhunen
- ▶ **Single Event Upsets and Hot Pixels in Digital Imagers** 41
Glenn H. Chapman, Rahul Thomas, Rohan Thomas, Klinsmann J. Coelho Silva Meneses, Tommy Q. Yang, Israel Koren and Zahava Koren
- ▶ **Accelerated Microarchitectural Fault Injection-Based Reliability Assessment** 47
Manolis Kaliorakis, Sotiris Tselonis, Athanasios Chatzidimitriou and Dimitris Gizopoulos

Session 3	Fault Tolerance
Date / Time	Monday, October 12, 2015 / 04:20 PM– 05:40 PM
Session Chair	Israel Koren, University of Massachusetts

- ▶ **Hot Spare Components for Performance-Cost Improvement in Multi-core SIMT** 53
S. Hasan Mozafari and Brett H. Meyer
- ▶ **Low-Overhead Fault-Tolerance for the Preconditioned Conjugate Gradient Solver** 60
Alexander Schöll, Claus Braun, Michael A. Kochte and Hans-Joachim Wunderlich
- ▶ **On-line Detection of Intermittent Faults in Digital-to-Analog Converters** 66
Mani Soma

- ▶ **A Dual-Layer Fault Manager for Systems based on Xilinx Virtex FPGAs** 72
I. Herrera-Alzu, M. López-Vallejo and C. Gil Soriano
- ▶ **REPAIR: Hard-Error Recovery via Re-Execution** 76
Jyothish Soman, Negar Miralaei, Alan Mycroft and Timothy M. Jones

Day 2: Tuesday – October 13, 2015

Session 4	Soft Errors
Date / Time	Tuesday, October 13, 2015 / 09:30 AM– 10:30 AM
Session Chair	Glenn Chapman , <i>Simon Fraser University</i>

- ▶ **A Method to Protect Bloom Filters from Soft Errors** 80
Pedro Reviriego, Salvatore Pontarelli, Juan Antonio Maestro and Marco Ottavi
- ▶ **Influence of Triple-Well Technology on Laser Fault Injection and Laser Sensor Efficiency** 85
N. Borrel, C. Champeix, E. Kussener, W. Rahajandraibe, M. Lisart, A. Sarafianos and J-M. Dutertre
- ▶ **Using Value Similarity of Registers for Soft Error Mitigation** 91
Abdulaziz Eker and Oguz Ergin

Session 5	Hardware Security
Date / Time	Tuesday, October 13, 2015 / 11:00 AM– 12:30 PM
Session Chair	Qiaoyan Yu , <i>University of New Hampshire</i>

- ▶ **Security Analysis of Logic Encryption Against the Most Effective Side-Channel Attack: DPA** 97
Muhammad Yasin, Bodhisatwa Mazumdar, Sk Subidh Ali and Ozgur Sinanoglu
- ▶ **Reliable Hash Trees for Post-quantum Stateless Cryptographic Hash-based Signatures** 103
Mehran Mozaffari-Kermani and Reza Azarderakhsh
- ▶ **Chip-level Anti-reverse Engineering using Transformable Interconnects** 109
Shuai Chen, Junlin Chen, Domenic Forte, Jia Di, Mark Tehranipoor and Lei Wang
- ▶ **Scan Attack on Elliptic Curve Cryptosystem** 115
Sk Subidh Ali and Ozgur Sinanoglu
- ▶ **Enhancing Embedded SRAM Security and Error Tolerance with Hardware CRC and Obfuscation** 119
Senwen Kan, Marco Ottavi and Jennifer Dworak
- ▶ **A BIST Approach for Counterfeit Circuit Detection based on NBTI Degradation** 123
Puneet Ramesh Savanur, Phaninder Alladi and Spyros Tragoudas

Session 6	Test Generation and Fault Simulation
Date / Time	Tuesday, October 13, 2015 / 01:40 PM – 03:00 PM
Session Chair	Prashant Joshi , <i>Cadence</i>

- ▶ **Quest for a Quantum Search Algorithm for Testing Stuck-at Faults in Digital Circuits** 127
Muralidharan Venkatasubramanian, Vishwani D. Agrawal and James J. Janaher
- ▶ **Piecewise-Functional Broadside Tests Based on Intersections of Reachable States** 133
Irith Pomeranz
- ▶ **Predictive LBIST Model and Partial ATPG for Seed Extraction** 139
G. Contreras, N. Ahmed, L. Winemberg and M. Tehranipoor

- ▶ **A CMOS Ripple Detector for Integrated Voltage Regulator Testing** 147
Cagatay Ozmen, Aydin Dirican, Nurettin Tan, Hieu Nguyen and Martin Margala
- ▶ **Adaptive Fault Simulation on Many-Core Microprocessor Systems** 151
Mohammad-Hashem Haghbayan, Sami Tervinen, Amir-Mohammad Rahmani, Pasi Liljeberg and Hannu Tenhunen

Session 7	Test Compaction and Compression
Date / Time	Tuesday, October 13, 2015 / 03:10 PM– 04:00 PM
Session Chair	Marco Ottavi , <i>University of Rome "Tor Vergata"</i>

- ▶ **Compacting Output Responses Containing Unknowns Using an Embedded Processor** 155
Kamran Saleem, Sreenivaas S. Muthyala and Nur A. Touba
- ▶ **Impact of Test Compression on Power Supply Noise Control** 161
Tengteng Zhang and D. M. H. Walker
- ▶ **Improving X-Tolerant Combinational Output Compaction via Input Rotation** 167
Asad Amin Bawa and Nur A. Touba

Session 8	Resilient Design and Technology
Date / Time	Tuesday, October 13, 2015 / 04.30 PM – 05:30 PM
Session Chair	Lorena Anghel , <i>TIMA Laboratory</i>

- ▶ **Low-Power LDPC Decoder Design Exploiting Memory Error Statistics** 171
Junlin Chen and Lei Wang
- ▶ **SEU Sensitivity and Modeling using Picosecond Pulsed Laser Stimulation of a D Flip-Flop in 40 NM CMOS Technology** 177
Clément Champeix, Nicolas Borrel, Jean-Max Dutertre, Bruno Robisson, Mathieu Lisart and Alexandre Sarafianos Pomeranz
- ▶ **Approximate Compressors for Error-Resilient Multiplier Design** 183
Zhixi Yang, Jie Han and Fabrizio Lombardi
- ▶ **Characterization of low power radiation-hard Reed-Solomon code protected serializers in 65-nm for HEP experiments electronics** 187
Daniele Felici, Sandro Bonacini and Marco Ottavi

Day 3: Wednesday – October 14, 2015

Session 9	Resiliency in Many-core Systems
Date / Time	Wednesday, October 14, 2015 / 09:00 AM – 10:10 AM
Session Chair	Cristiana Bolchini , <i>Politecnico di Milano</i>

- ▶ **Reducing the Performance Overhead of Resilient CMPs with Substitutable Resources** 191
A. Malek, S. Tzilis, D. A. Khan, I. Sourdis, G. Smaragdous, C. Strydis
- ▶ **Dependable Real-Time Task Execution Scheme for a Many-Core Platform** 197
Tomohiro Yoneda, Masashi Imai, Hiroshi Saito and Kenji Kise
- ▶ **Towards Reliability and Performance-Aware Wireless Network-on-Chip Design** 205
Michael Opoku Agyeman, Kin-Fai (Kenneth) Tong and Terrence Mak

- ▶ **A Fast and Scalable Fault Injection Framework to Evaluate Multi/Many-core Soft Error Reliability** 211
Felipe Rosa, Fernanda Kastensmidt, Ricardo Reis and Luciano Ost

Session 10	Error Prediction, Detection and Diagnosis
Date / Time	Wednesday, October 14, 2015 / 10:40 AM– 11:50 PM
Session Chair	Felipe França , <i>Federal University of Rio de Janeiro</i>

- ▶ **A Cross-layer Approach to Online Adaptive Reliability Prediction of Transient Faults** 215
Bahar Farahani and Saeed Safari
- ▶ **A Non-Conservative Software-Based Approach for Detecting Illegal CFEs Caused by Transient Faults** 221
Diego Rodrigues, Ghazaleh Nazarian, Álvaro Moreira, Luigi Carroand Georgi Gaydadjiev
- ▶ **A Configurable Board-level Adaptive Incremental Diagnosis Technique based on Decision Trees** 227
Cristiana Bolchini and Luca Cassano
- ▶ **IntelliCAN: Attack-Resilient Controller Area Network (CAN) for Secure Automobiles** 233
Mohammad Raashid Ansari, Shucheng Yu and Qiaoyan Yu